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Technical Compliance

No. ACS-E21199

The following product has been tested by us with the listed standards and found in compliance with the council EMC directive 2014/30/EU. It is demonstrative for the compliance with this EMC Directive.

Applicant : Shenzhen Century Cloud Core Technologies Limited
 F1-F5, B1 Complex Building, Gangtou Industrial Park, Yabian
 Community, Shajing Town, Baoan District, Shenzhen

Product : SERVER

Model No. : 240-Cd

Test Standards:	
EN 55032: 2015+A11: 2020 (Class A) EN 55032: 2015	Electromagnetic compatibility of multimedia equipment - Emission requirements
EN IEC 61000-3-2: 2019	Electromagnetic compatibility(EMC) Part 3-2:Limits-Limits for harmonic current emissions(equipment input current $\leq 16A$ per phase)
EN 61000-3-3: 2013+A1: 2019	Electromagnetic compatibility(EMC) Part 3-3:Limits-Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current $\leq 16A$ per phase and not subject to conditional connection
EN 55035: 2017 EN 55035: 2017+A11: 2020	Electromagnetic compatibility of multimedia equipment — Immunity requirements
IEC 61000-4-2: 2008	Electrostatic Discharge
IEC 61000-4-3: 2006+A1: 2007+A2: 2010	RF Field Strength Susceptibility
IEC 61000-4-4: 2012	Electrical Fast Transients
IEC 61000-4-5: 2014+A1: 2017	Surge
IEC 61000-4-6: 2013	Continuous Conducted disturbance
IEC 61000-4-8: 2009	Magnetic Field Immunity
IEC 61000-4-11: 2004+A1: 2017	Immunity to Voltage Interruption Variation



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 Audix Technology (Shenzhen) Co., Ltd.
 EMC 部門報告專用章
 Stamp only for EMC Dept. Report
 Signature: *Bensun Chen*

Bensun Chen
 Manager
 Date: Jun.25, 2021

The technical compliance is based on a single evaluation of one sample of above mentioned product. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.